

1	<b>MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT</b>	39	...Sound energy (e.g., ultrasonic)
2	.Earth science	40	...Radiant energy (e.g., X-ray, infrared, laser)
3	..Weather	41	..Force or torque measurement
4	...Lightning	42	...Stress or strain measurement
5	..Topography (e.g., land mapping)	43	....Torsional, shear, tensile, or compression
6	..Well logging or borehole study	44	...Mechanical work or power measurement
7	...By induction or resistivity logging tool	45	..Flow metering
8	...By radiation (e.g., nuclear, gamma, X-ray)	46	...Count or pulse
9	...Drilling	47	...Pressure, resistive, or capacitive sensor
10	...Dipmeter	48	...Acoustic
11	...Formation characteristic	49	...Radiant energy
12	....Fluid flow investigation	50	..Fluid measurement (e.g., mass, pressure, viscosity)
13	....Hydrocarbon prospecting	51	...Leak detecting
14	..Seismology	52	...Capacitive sensor
15	...Earthquake or volcanic activity	53	...Resistive sensor
16	...Specific display system (e.g., mapping, profiling)	54	...Acoustic or vibration sensor
17	...Filtering or noise reduction/removal	55	...Liquid level or volume determination
18	...Velocity of seismic wave	56	..Vibration detection
19	..Biological or biochemical	57	..Electrical signal parameter measurement system
20	..Gene sequence determination	58	..For electrical fault detection
21	..Cell count or shape or size analysis (e.g., blood cell)	59	...Fault location
22	..Chemical analysis	60	..Power parameter
23	..Quantitative determination (e.g., mass, concentration, density)	61	...Power logging (e.g., metering)
24	..Gaseous mixture (e.g., solid-gas, liquid-gas, gas-gas)	62	....Including communication means
25	..Liquid mixture (e.g., solid-liquid, liquid-liquid)	63	...Battery monitoring
26	..By particle count	64	..Voltage or current
27	..Molecular structure or composition determination	65	...Including related electrical parameter
28	...Using radiant energy	66	..Waveform analysis
29	..Particle size determination	67	...Display of waveform
30	..Chemical property analysis	68	....Having specified user interface (e.g., marker, menu)
31	..Specific operation control system	69	...Signal quality (e.g., timing jitter, distortion, signal-to-noise ratio)
32	..Specific signal data processing	70	...Waveform extraction
33	..Mechanical measurement system	71	...Waveform-to-waveform comparison
34	..Wear or deterioration evaluation	72	....Phase comparison
35	..Flaw or defect detection	73	....Identification of waveform
36	...Location	74	....Signal-in-signal determination
38	...Electromagnetic (e.g., eddy current)	75	...Frequency
		76	....Frequency spectrum
		77	....Using Fourier method

78	....By count (e.g., pulse)	118	..Testing multiple circuits
79	..Time-related parameter (e.g., pulse-width, period, delay, etc.)	119	..Including program initialization (e.g., program loading) or code selection (e.g., program creation)
80	..Specified memory location generation for storage	120	..Including input/output or test mode selection means
81	.Quality evaluation	121	.Including multiple test instruments
82	..Having judging means (e.g., accept/reject)	122	.Including specific communication means
83	..Sampling Inspection Plan	123	.Including program set up
84	..Quality control	124	.Signal generation or waveform shaping
85	<b>CALIBRATION OR CORRECTION SYSTEM</b>	125	..Timing signal
86	.Linearization of measurement	126	..Signal conversion
87	.Zeroing (e.g., null)	127	<b>MEASUREMENT SYSTEM</b>
88	.Zero-full scaling	128	.Article count or size distribution
89	.Timing (e.g., delay, synchronization)	129	..Quantitative determination by weight
90	.Error due to component compatibility	130	.Temperature measuring system
91	..Having interchangeable sensors or probes	131	..Body temperature
92	.Direction (e.g., compass)	132	..Thermal protection
93	..By another sensor	133	..By resistive means
94	.Position measurement	134	..By radiant energy
95	..Coordinate positioning	135	...Infrared
96	.Speed	136	..Thermal related property
97	.Length, distance, or thickness	137	.Density
98	.Pressure	138	.Pressure
99	.Temperature	139	..Exerted on or by a living body
100	.Fluid or fluid flow measurement	140	..Within an enclosure
101	.Weight	141	.Accelerometer
102	..Tare weight adjusted	142	.Speed
103	.Acoustic	143	..By radar or sonar
104	.Sensor or transducer	144	..Of aircraft
105	.For mechanical system	145	..Rotational speed
106	.Signal frequency or phase correction	146	...Averaging performed
107	.Circuit tuning (e.g., potentiometer, amplifier)	147	...Specific mathematical operation performed
108	<b>TESTING SYSTEM</b>	148	....For wheel speed
109	.For transfer function determination	149	..By distance and time measurement
110	..Binary signal stimulus (e.g., pulse)	150	.Orientation or position
111	..Noise signal stimulus (e.g., white noise)	151	..Angular position
112	..Sinusoidal signal stimulus	152	..3D position
113	.Of mechanical system	153	...3D orientation
114	..Pneumatic or hydraulic system	154	..Inclinometer
115	..Electromechanical or magnetic system	155	.Dimensional determination
116	.Of sensing device	156	..Area or volume
117	.Of circuit	157	..Radius or diameter
		158	..Linear distance or length

159 ...By reflected signal (e.g., ultrasonic, light, laser)  
 160 ...Pedometer  
 161 ...Electronic ruler  
 162 ...Micrometer  
 163 ...By rotary encoding means  
 164 ...Electronic tape measure  
 165 ...Odometer  
 166 ..Height or depth  
 167 ..Contouring  
 168 ...By probe (e.g., contact)  
 169 ...Center of gravity  
 170 ..Thickness or width  
 171 ...By ultrasonic  
 172 ...By radiant energy (e.g., X-ray, light)  
 173 ..Weight  
 174 ..Payload  
 175 ..Of moving article  
 176 ..Time duration or rate  
 177 ..Due time monitoring (e.g., medication clock, maintenance interval)  
 178 ..Timekeeping (e.g., clock, calendar, stopwatch)  
 179 ..Statistical measurement  
 180 ..Histogram distribution  
 181 ..Probability determination  
 182 ..Performance or efficiency evaluation  
 183 ..Diagnostic analysis  
 184 ...Maintenance  
 185 ...Cause or fault identification  
 186 ..Computer and peripheral benchmarking  
 187 ..History logging or time stamping  
 188 ..Remote supervisory monitoring  
 189 ..Measured signal processing  
 190 ..Signal extraction or separation (e.g., filtering)  
 191 ...For noise removal or suppression  
 193 ....By threshold comparison  
 194 ....By mathematical attenuation (e.g., weighting, averaging)  
 195 .....Subtracting noise component  
 196 ..Using matrix operation  
 197 ....Having multiple filtering stages  
 198 ..Measurement conversion processing (e.g., true-to-RMS value)  
 199 ..Averaging

**FOREIGN ART COLLECTIONS**FOR 000 **CLASS-RELATED FOREIGN DOCUMENTS**

Any foreign patents or non-patent literature from subclasses that have been reclassified have been transferred directly to FOR Collections listed below. These Collections contain ONLY foreign patents or non-patent literature. The parenthetical references in the Collection titles refer to the abolished subclasses from which these Collections were derived.

**APPLICATIONS (364/400)**

FOR 100 ..Earth sciences (e.g., weather) (364/420)  
 FOR 101 ..Seismology (364/421)  
 FOR 102 ..Well logging (364/422)  
 FOR 103 ..Electrical/electronic engineering (364/480)  
 FOR 104 ..Measuring or testing (364/481)  
 FOR 105 ...Impedance (364/482)  
 FOR 106 ...Voltage, current, or power (364/483)  
 FOR 107 ...Frequency (364/484)  
 FOR 108 ....Frequency spectrum (364/485)  
 FOR 109 ...Pulse (364/486)  
 FOR 110 ..Waveform (364/487)  
     ..Electrical/electronic engineering (364/480)  
 FOR 111 ..Power generation or distribution (364/492)  
 FOR 112 ...Economic dispatching (364/493)  
 FOR 113 ...Turbine or generator control (364/494)  
 FOR 114 ...With model (364/495)  
 FOR 115 ..Chemical and engineering sciences (364/496)  
 FOR 116 ..Chemical analysis (364/497)  
 FOR 117 ...Spectrum analysis (composition) (364/498)  
 FOR 118 ...Chemical property (364/499)  
 FOR 119 ..Chemical process control (364/500)  
 FOR 120 ...Distillation (364/501)  
 FOR 121 ...Physical mixing or separation (364/502)  
 FOR 122 ...Kilns (364/503)

- FOR 123 ..Mechanical and civil engineering (364/505)
- FOR 124 ...Measuring or testing (364/506)
- FOR 125 ....Flaw or defect (364/507)
- FOR 126 ....Stress, strain, or vibration (364/508)
- FOR 127 ....Fluid (364/509)
- FOR 128 ....Fluid flow (364/510)
- FOR 129 ....Power (364/511)
- FOR 130 ..Physics (364/524)
- FOR 131 ..Optics or photography (364/525)
- FOR 132 ...Color analysis (364/526)
- FOR 133 ..Atomic or nuclear physics (364/527)
- FOR 134 **MEASURING, TESTING, OR MONITORING (364/550)**
- FOR 135 ..Measuring and evaluating (e.g., performance) (364/551.01)
- FOR 136 ..Of machine tool (364/551.02)
- FOR 137 ..Quality control determinations (364/552)
- FOR 138 ..Transfer function evaluation (364/553)
- FOR 139 ..Statistical data (e.g., stochastic variable) (364/554)
- FOR 140 ..Particle count, distribution, size (364/555)
- FOR 141 ..For basic measurements (364/556)
- FOR 142 ..Temperature (364/557)
- FOR 143 ..Pressure or density (364/558)
- FOR 144 ..Orientation (364/559)
- FOR 145 ..Dimension (364/560)
- FOR 146 ...Distance (364/561)
- FOR 147 ....Length or height (364/562)
- FOR 148 ....Width or thickness (364/563)
- FOR 149 ...Area or volume (364/564)
- FOR 150 ..Rate of change of dimension (e.g., speed) (364/565)
- FOR 151 ..Acceleration and further derivatives (364/566)
- FOR 152 ..Weight (364/567)
- FOR 153 ...Basis weight (364/568)
- FOR 154 ..Time or time intervals (364/569)
- FOR 155 ..Operations performed (364/570)
- FOR 156 ..Calibration or compensation
- FOR 157 ...Having mathematical operation on initial measurement data (364/571.02)
- FOR 158 ....Including environmental factors (e.g., temperature) (364/571.03)
- FOR 159 ....Including predetermined stored data (364/571.04)
- FOR 160 ....Using difference involving initial measurement data (364/571.05)
- FOR 161 ....Using analog calculating elements (364/571.06)
- FOR 162 ...By table look-up (364/571.07)
- FOR 163 ...Using operator provided data (364/571.08)
- FOR 164 ..Filtering (364/572)
- FOR 165 ..Linearization (364/573)
- FOR 166 ..Noise reduction (364/574)
- FOR 167 ..Averaging (364/575)
- FOR 168 ..Fourier analysis (364/576)
- FOR 169 ..Interpolation/extrapolation (364/577)
- FOR 170 ..With control of testing or measuring apparatus (364/579)
- FOR 171 ..Programmed testing conditions (364/580)
- FOR 172 ..Weighting (364/581)
- FOR 173 ..Normalization (364/582)